



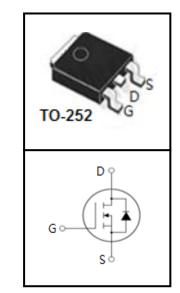
# **30V N-Channel Trench MOSFET**

### FEATURES

- Super Low Gate Charge
- 100% EAS Guaranteed
- RoHS compliant
- Green Device Available
- Excellent CdV/dt effect decline
- Advanced high cell density Trench technology

### **APPLICATIONS**

- Switch Mode Power Supply (SMPS)
- Uninterruptible Power Supply (UPS)
- Hard switched and high frequency circuits



RoHS

Device Marking and Package Information				
Device	Package	Marking		
CTD03N8P5	TO-252	CTD03N8P5		

<b>Absolute Maximum Ratings</b> at $T_j = 25^{\circ}C$ unless otherwise noted				
Parameter		Symbol	Value	Unit
Drain-Source Voltage (V <sub>GS</sub> = 0V)		V <sub>DSS</sub>	30	V
Continuous Drain Current $T_c = 25^{\circ}C$	(note1)		60	A
Continuous Drain Current $T_c = 100^{\circ}C$	(note1)	I <sub>D</sub>	40	A
Pulsed Drain Current	(note2)	I <sub>DM</sub>	120	A
Gate Source Voltage		V <sub>GSS</sub>	±20	V
Single Pulse Avalanche Energy	(note3)	E <sub>AS</sub>	57.8	mJ
Power Dissipation	(note4)	P <sub>D</sub>	41	W
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	-55~+175	°C

Thermal Characteristics				
Parameter		Symbol	Value	Unit
Thermal Resistance, Junction-Case	(note1)	$R_{ extsf{ heta}JC}$	3.6	°C/W
Thermal Resistance, Junction-Ambient	(note1)	$R_{ extsf{ heta}JA}$	62	-0/10



## CTD03N8P5

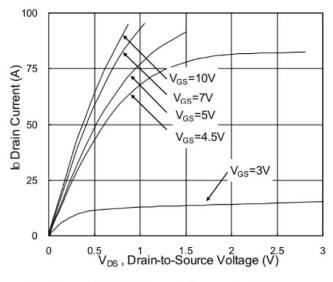
<b>Electrical Characteristics</b> $T_j = 25^{\circ}C$ unless otherwise specified							
Parameter		<b>T</b> ( <b>0</b> ))))	Value				
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0V, I_D = 250\mu A$	30			V	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{DS} = 24V, V_{GS} = 0V, T_{J} = 25^{\circ}C$			1	uA	
	.035	$V_{DS} = 24V, V_{GS} = 0V, T_{J} = 55^{\circ}C$			5	uA	
Gate-Source Leakage	I <sub>GSS</sub>	$V_{GS}$ = $\pm 20 V$			±100	nA	
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_D = 250 \mu A$	1.2		2.5	V	
Drain-Source On-Resistance (note3)	Read	$V_{GS} = 10V, I_{D} = 30A$		7.3	8.5	mΩ	
Drain-Source On-Resistance (notes)	R <sub>DS(on)</sub>	$V_{GS} = 4.5 V, I_{D} = 15 A$		11	14	mΩ	
Dynamic							
Input Capacitance	C <sub>iss</sub>	V <sub>GS</sub> = 0V,		1317	1843	pF	
Output Capacitance	C <sub>oss</sub>	$V_{DS} = 15V,$		163	228		
Reverse Transfer Capacitance	C <sub>rss</sub>	f = 1.0MHz		131	183		
Total Gate Charge	Q <sub>g</sub>			12.6	17.6	nC	
Gate-Source Charge	Q <sub>gs</sub>	$V_{DD} = 15V, I_{D} = 15A, V_{GS} = 4.5V$		4.2	5.9		
Gate-Drain Charge	$Q_{gd}$			5.1	7.1		
Turn-on Delay Time	t <sub>d(on)</sub>			4.6	9.2		
Turn-on Rise Time	t <sub>r</sub>	V <sub>DS</sub> = 15V, I <sub>D</sub> = 15A		12.2	22	ns	
Turn-off Delay Time	t <sub>d(off)</sub>	$V_{GS} = 10V, R_G = 3.3\Omega$		26.6	53		
Turn-off Fall Time	t <sub>f</sub>			8	16		
Body Diode Characteristics							
Continuous Body Diode Current	۱ <sub>s</sub>				60	· A	
Pulsed Diode Forward Current	I <sub>SM</sub>	$T_{\rm C} = 25^{\circ}{\rm C}$			120		
Body Diode Voltage	V <sub>SD</sub>	$T_J = 25^{\circ}C, I_{SD} = 5A, V_{GS} = 0V$			1.2	V	
Reverse Recovery Time	t <sub>rr</sub>	I <sub>F</sub> = 30A		9.2		ns	
Reverse Recovery Charge	Q <sub>rr</sub>	$di_F/dt = 100A/\mu s$		2.0		nC	

#### Notes

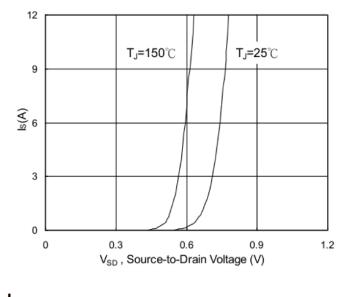
- 1. The data tested by surface mounted on a 1 inch2 FR-4 board with 2OZ copper.
- 2. The data tested by pulsed , pulse width  $\!\!\!\leq\!\!300 us$  , duty cycle  $\!\!\!\leq\!\!2\%$
- 3. The EAS data shows Max. rating . The test condition is VDD =25V, VGS =10V, L=0.1mH
- 4. The power dissipation is limited by 175°C junction temperature
- 5. The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.



### **Typical Characteristics** $T_J = 25^{\circ}C$ , unless otherwise noted



**Fig.1 Typical Output Characteristics** 



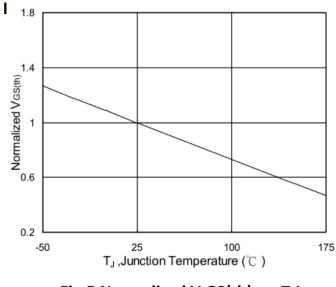


Fig.5 Normalized V GS(th) vs. T J

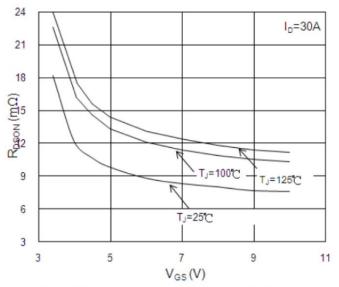
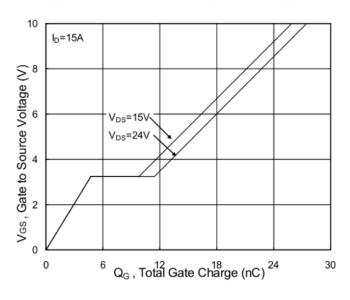


Fig.2 On-Resistance vs. G-S Voltage



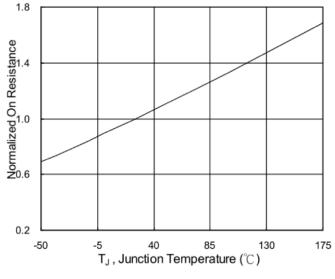


Fig.6 Normalized R DSON vs. T J



### **Typical Characteristics** $T_J = 25^{\circ}C$ , unless otherwise noted

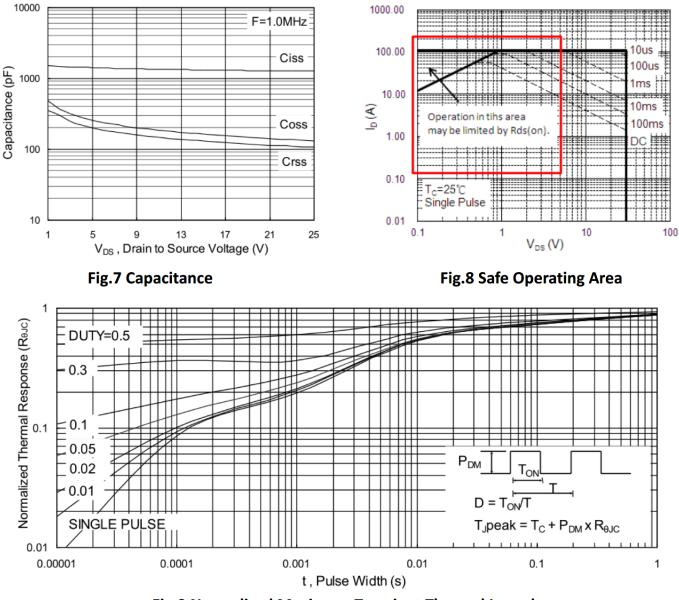


Fig.9 Normalized Maximum Transient Thermal Impedance





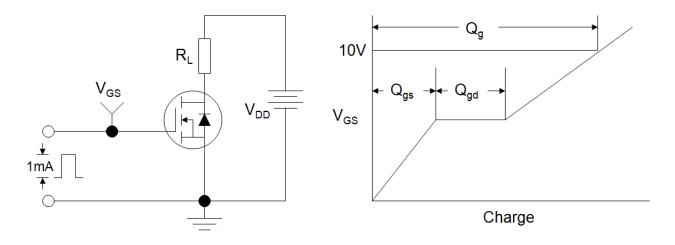


Figure B: Resistive Switching Test Circuit and Waveform

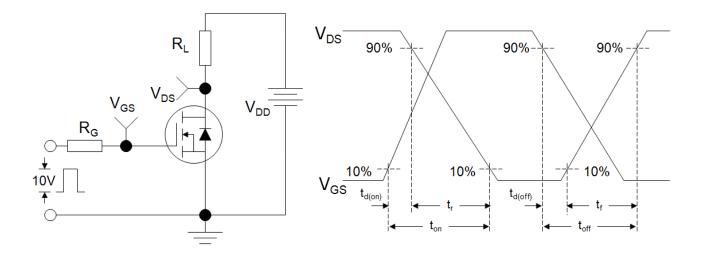
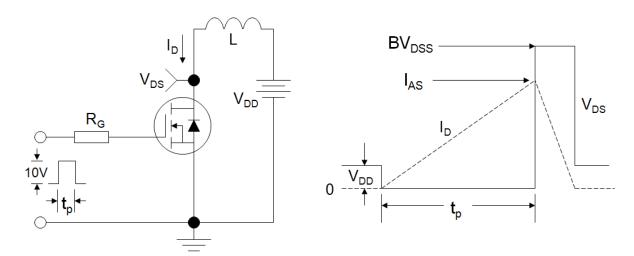


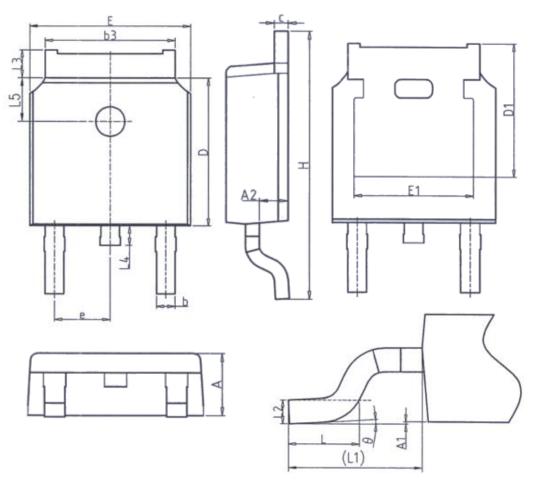
Figure C: Unclamped Inductive Switching Test Circuit and Waveform







TO-252



Unit: mm			
Symbol	Min.	Max.	
A	2.20	2.40	
A1	0.00	0.20	
A2	0.97	1.17	
b	0.68	0.90	
b3	5.20	5.50	
с	0.43	0.63	
D	5.98	6. 22	
D1	5. 30REF		
E	6.40	6.80	
E1	4.63	-	

Unit: mm				
Symbol	Min. Max.			
e	2. 286BSC			
Н	9.40	10.50		
L	1.38	1.75		
L1	2.90REF			
L2	0. 51BSC			
L3	0.88	1.28		
L4	_	1.00		
L5	1.65	1.95		
θ	0°	8°		

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